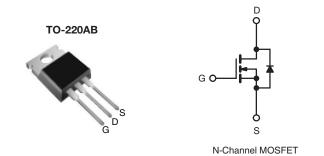


Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	500			
R _{DS(on)} (Ω)	V _{GS} = 10 V 3.0			
Q _g (Max.) (nC)	17			
Q _{gs} (nC)	4.3			
Q _{gd} (nC)	8.5			
Configuration	Single			



FEATURES

• Low Gate Charge Qq Results in Simple Drive



 Improved Gate, Avalanche and Dynamic dV/dt RoHS Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage and current
- Effective Coss Specified
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Two Transistor Forward
- Half bridge
- Full bridge

ORDERING INFORMATION	
Package	TO-220AB
Lead (Pb)-free	IRF820APbF
Lead (FD)-II-ee	SiHF820A-E3
SnPb	IRF820A
On D	SiHF820A

PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	500	V	
Gate-Source Voltage		V_{GS}	± 30		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}\text{C}$	L-	2.5	А	
	$T_C = 100 ^{\circ}C$	I _D	1.6		
Pulsed Drain Current ^a		I _{DM}	10	1	
Linear Derating Factor			0.40	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	140	mJ	
Repetitive Avalanche Currenta		I _{AR}	2.5	Α	
Repetitive Avalanche Energy ^a	E _{AR}	5.0	mJ		
Maximum Power Dissipation $T_C = 25 ^{\circ}C$		P _D	50	W	
Peak Diode Recovery dV/dtc	dV/dt	3.4	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s		-	300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF IVI3 SCIEW		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Starting $T_J = 25$ °C, L = 45 mH, $R_g = 25$ Ω , $I_{AS} = 2.5$ A (see fig. 12). c. $I_{SD} \le 2.5$ A, $dI/dt \le 270$ A/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5	

PARAMETER	SYMBOL	TEST	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	to 25 °C, I _D = 1 mA	-	0.60	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	$V_{DS} = V_{GS}, I_D = 250 \mu A$		-	4.5	V
Gate-Source Leakage	I _{GSS}	V _G	_S = ± 30 V	-	-	± 100	nA
Zoro Coto Voltogo Duoin Current		V _{DS} = 5	00 V, V _{GS} = 0 V	-	-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 400 V, \	/ _{GS} = 0 V, T _J = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.5 A ^b	-	-	3.0	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = 5$	0 V, I _D = 1.5 A ^b	1.4	-	-	S
Dynamic		<u>.</u>					
Input Capacitance	C _{iss}	V	_{GS} = 0 V,	-	340	-	
Output Capacitance	C _{oss}	V _I	$V_{DS} = 25 \text{ V},$		53	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5 $V_{GS} = 0 \text{ V}$; $V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$		-	2.7	-	pF
Output Capacitance	C _{oss}				490		
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V}; V_{DS}$	s = 400 V, f = 1.0 MHz		15		
Effective Output Capacitance	Coss eff.	V _{GS} = 0 V; \	V _{DS} = 0 V to 400 V ^c		28		
Total Gate Charge	Qg			-	-	17	
Gate-Source Charge	Q_{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 2.5 \text{ A, } V_{DS} = 400 \text{ V,}$ see fig. 6 and 13 ^b	-	-	4.3	nC	
Gate-Drain Charge	Q _{gd}	1	ooo ng. o ana ro	-	-	8.5	
Turn-On Delay Time	t _{d(on)}			-	8.1	-	
Rise Time	t _r	V _{DD} = 2 ¹	V _{DD} = 250 V, I _D = 2.5 A,		12	-	ns
Turn-Off Delay Time	t _{d(off)}	$R_g = 21 \Omega$, $R_D = 97 \Omega$, see fig. 10^b		-	16	-	
Fall Time	t _f			-	13	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbo	MOSFET symbol showing the		-	2.5	- A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	10	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, \text{Is}$	$T_J = 25 ^{\circ}\text{C}, I_S = 2.5 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	1.6	V
Body Diode Reverse Recovery Time	t _{rr}	T 25 °C !	2.5.4. dl/dt = 100.4/usb	-	330	500	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 2.5 \text{A}, dI/dt = 100 \text{A/}\mu\text{s}^b$			760	1140	nC
Forward Turn-On Time	t _{on}	Intrinsic turn	-on time is negligible (turn	-on is do	minated b	y L _S and	L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %. c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

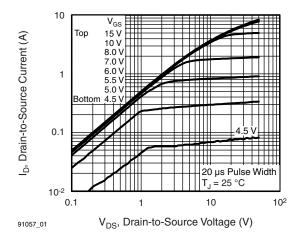


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

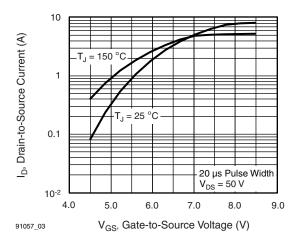


Fig. 3 - Typical Transfer Characteristics

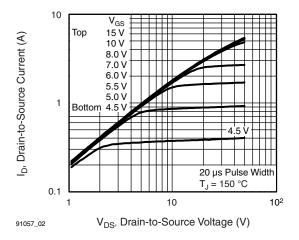


Fig. 2 - Typical Output Characteristics, T_{C} = 150 $^{\circ}C$

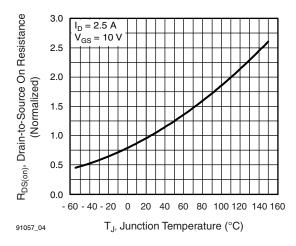


Fig. 4 - Normalized On-Resistance vs. Temperature



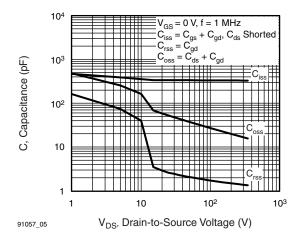


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

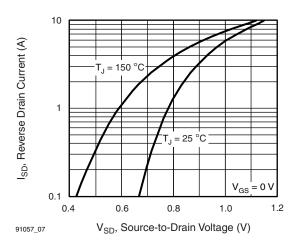


Fig. 7 - Typical Source-Drain Diode Forward Voltage

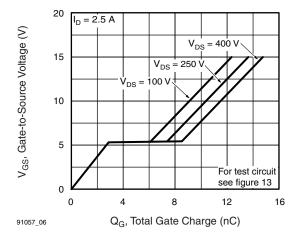


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

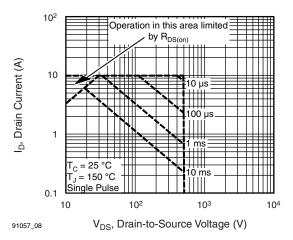


Fig. 8 - Maximum Safe Operating Area



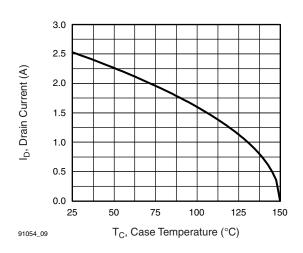


Fig. 9 - Maximum Drain Current vs. Case Temperature

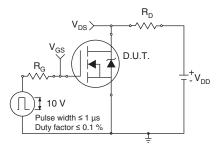


Fig. 10a - Switching Time Test Circuit

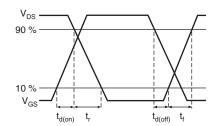


Fig. 10b - Switching Time Waveforms

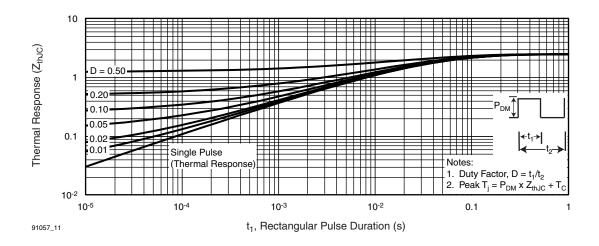


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



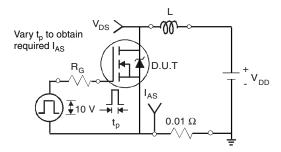


Fig. 12a - Unclamped Inductive Test Circuit

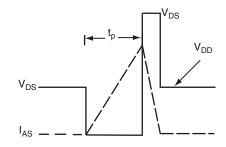


Fig. 12b - Unclamped Inductive Waveforms

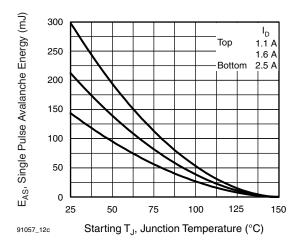


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

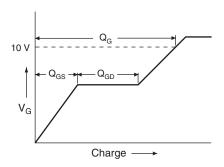


Fig. 12d - Basic Gate Charge Waveform

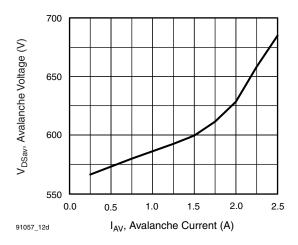


Fig. 13a - Typical Drain-to-Source Voltage vs.
Avalanche Current

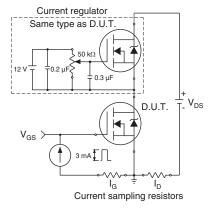
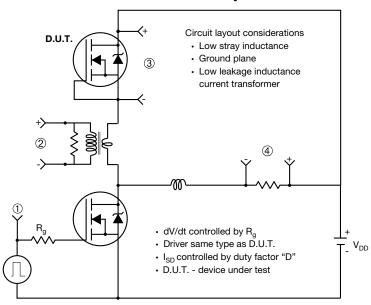


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



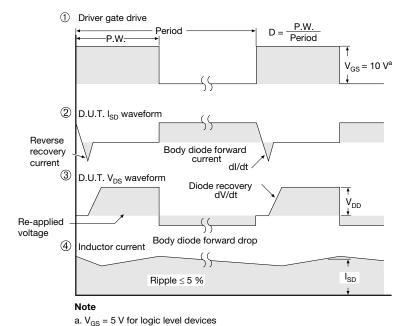


Fig. 14 - For N-Channel

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TO-220-1



DIM.	MILLIN	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
Е	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	

Note

 \bullet $M^{\star}=0.052$ inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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